

High-reliability discrete products and engineering services since 1977

ZR01F-HR

Screening Procedure

Inverted Series Diode

ZR01F-HR SCREENING PROCEDURES

All ZR01F-HR procured shall be 100% screened in accordance with the following procedures, as applicable. Unless otherwise noted, all testing is performed at room temperature.

REFERENCE: MIL-PRF-19500 and Leach 002-4692-XXX-000 AG

TEST/PROCESS		SPEC/METHOD	CONDITIONS
1	Temperature Cycle	MIL-STD-750/Methond 1051	Condition C, 20 cycles from -55°C to +175°C. Minimum 10 minute dwell at each extreme.
2	Impact Ambient	002-4692-XXX-000	$T_A = 25$ °C. Perform electrical testing per Table I, Group A, Subgroup 2. Data by attributes.
3	Burn-in Load	MIL-STD-750	Load parts on Digitron programmable burn-in boards. Ensure all parts are loaded with positive polarity to the green dot (Zener end).
4	Power Burn-in	MIL-STD-750/Method 1038B	Power burn shall be 96 hours minimum. $I_Z = 0.5 \text{ mA}$, $T_A = 125^{\circ}\text{C}$ minimum. Parts shall be tested within 96 hours of removal of burn-in bias.
5	Burn-in Unload	MIL-STD-750	Remove parts from burn-in boards. Inspect parts for damage.
6	Impact Ambient	002-4692-XXX-000	T _A = 25°C. Perform electrical testing per Table I, Group A, Subgroup 2. Data by attributes.
7	PDA Calculation	MIL-PRF-19500	Calculate PDA. 10% maximum for burnin and post burn-in electrical test failures.